

Scanning Spectrometer



SIR-2600 Compact, Extended Range Spectrometer

The SIR-2600 Scanning Spectrometer collects spectral data from 0.9 μm to 2.6 μm wavelength range. The SIR2600's fiber-based system uses a unique design that allows rapid spectral scans over its entire range. It can also provide real-time data from several discrete wavelengths. The compact design allows you to integrate the SIR-2600 easily into OEM applications and online process environments.

The SIR-2600 uses a single point detector and a high angular resolution-tunable grating system. The zero-backlash mechanical design provides superior accuracy and repeatability. This combination, along with an innovative 24-bit A/D converter, provides high spectral resolution and very high signal-to-noise data.

An optional filter wheel provides optical order sorting of diffracted orders.

The SIR-2600 is designed with a rugged aluminum housing that is robust enough to withstand the rigors of chemical processing applications.

The USB 2.0-compliant interface provides fast data transfers and our included software can be used to control all of the SIR-2600's functions as well as analyze data.

Specifications

Range:	0.9 μm - 2.6 μm
Detector:	Extended Range InGaAs with 2-stage cooler
Diffraction grating:	600 lines/mm 1.5 μm blaze
Optical design:	Czerny-Turner F/3
Slits available:	10 μm , 50 μm , 100 μm , 200 μm , 500 μm
Optical input:	SMA-905/906 with optional lensed input
Analog resolution:	24 bits 16,777,216 counts
Triggering options:	Internal and external synchronization, pulse width control and phase delay
Additional digital outputs:	2 channel selectable 3.3V/5V output
Additional digital inputs:	2 channels 3.3V/5V compatible inputs
Grating steps in range:	45000
Step accuracy:	+/- 10 steps
Data interface:	USB 2.0
Scan time:	As quick as 20 seconds
Resolution based on optical slits:	

Scanning Spectrometer



SIR-3400 Compact, Extended Range Spectrometer

The SIR-3400 Mid-Infrared Fiber Optic Analyzer is a first for optical-based infrared spectrometers. This SIR scanning spectrometer collects spectral data over the 1-3.4 μm wavelength range and features a fiber-based system for rapid spectral scans over its entire range. It can also provide real-time data from several discrete wavelengths.

The SIR-3400 uses a single point detector and a high angular resolution-tunable grating system. The zero-backlash mechanical design provides superior accuracy and repeatability. This combination, along with an innovative 24-bit A/D converter, provides high spectral resolution and very high signal-to-noise data.

An optional filter wheel provides optical order sorting of diffracted orders.

The SIR-3400 is designed with a rugged aluminum housing that is robust enough to withstand the rigors of chemical processing applications.

The USB 2.0-compliant interface provides fast data transfers and our included software can be used to control all of the SIR-3400's functions as well as analyze data.

Specifications

Range:	1-3.4 μm
Detector:	InAs with 3 stage cooler
Diffraction grating:	300 lines/mm 2.0 μm blaze
Optical design:	Czerny-Turner F/3
Slits available:	10 μm , 50 μm , 100 μm , 200 μm , 500 μm
Optical input:	SMA-905/906 with optional lensed input
Analog resolution:	24 bits 16,777,216 counts
Triggering options:	Internal and external synchronization, pulse width control and phase delay
Additional digital outputs:	2 channel selectable 3.3V/5V output
Additional digital inputs:	2 channels 3.3V/5V compatible inputs
Grating steps in range:	16,800
Step accuracy:	+/- 10 steps
Data interface:	USB 2.0
Scan time:	As quick as 20 seconds
Resolution based on optical slits:	10 μm .22 nm 50 μm 1.1 nm 100 μm 2.22 nm 200 μm 5 nm 500 μm 11 nm